

# JTC1/SC22/WG15 - RCT N069

**Date:** July 13, 1995

**Supersedes:** N/A

**Title/Topic:** Meeting Minutes for  
Nashua, New Hampshire  
July 13, 1995

**Source:** Secretary RGCT

Action Requested(check one):

*Review/Comment by:*

*Respond by:*

*For discussion/consideration @ RGCT meeting*

*For distribution*

*For information*

*Other(see details)*

*Details:*

**MEETING MINUTES**  
JTC1/SC22/WG15 Rapporteur Group on Conformance Testing  
July 13, 1995  
Nashua, New Hampshire, USA

**1.0 Opening of Meeting**

**1.1 Welcome, Introductions, and Roll Call**

RGCT was held in conjunction with the IEEE PASC Test Methods meeting at Nashua, NH, USA. The RGCT meeting was informal and only have one item on the agenda. The meeting was opened by Jerry Powell at 13:30 on July 13, 1995.

**1.2 Selection of recording secretary**

Jerry Powell volunteered to take the minutes.

**1.3 Selection of drafting committee**

It was decided that such a small committee could effectively use the whole committee for drafting.

**1.4 Adoption of agenda**

The RGCT meeting was called to Review and comment on the EWOS Technical Guide on Open System Environment Conformance Testing and to review and comment on the EWOS Technical Guide on Conformance Testing Vocabulary.

**1.5 Approval of minutes**

The minutes from the last meeting in Enschede, The Netherlands will be addressed at the next formal RGCT meeting.

**2.0 Review and Comment on EWOS Technical Guide on Conformance Testing Vocabulary**

The RGCT and PASC P2003 Test Methods Group reviewed this document and the comments are attached to these minutes..

**3.0 Review and Comment on EWOS Technical Guide on Open System Environment Conformance Testing**

EWOS was not able to make this document available. Dave Rayner stated that it was not ready to be reviewed.

**4.0 New Business**

4.1 No new business

**5.0 Closing Process**

**5.1 Document Number Assignment**

N069 - Minutes from the Nashua meeting.

**5.2 Thanks to Host**

The RGCT wishes to thank the IEEE PASC P2003 Test Methods group for allowing us to meet jointly with them.

**5.3 Adjourn**

Adjourned July 13, 1995 at 14:30.

RGCT and 2003 Plenary Attendance List

<u>Name</u>	<u>Organization</u>	<u>Mon</u>	<u>Thur</u>
<b>Test Methods Members</b>			
Barry Hedquist - 2003 Chair	Perennial	X	X
Jerry Powell - RGCT Lead Rapporteur	IBM	X	X
Lowell Johnson	Unisys	X	X
Kathy Liburdy	Clemson	X	X
Khaled Al-Ali	Tandem	X	X
Bill Branum	Cray	X	
John Davies	DISA/JITC	X	X
Sheila Frankel	NIST	X	X
Bruce Weiner	Mindcraft	X	X
Dirk Coldewey	Tandem	X	
Roger Martin	NIST		X
Kenneth Thomas	DISA/JITC		X
Sandra Sweringen	US Air Force		X
Norm Eaglestone	SunSoft		X

**RGCT Review and Comment of  
Conformance Testing Vocabulary  
Revision of ETG 009  
Third Draft - Version 3.0**

**10 July 1995**

**D. Rayner**

The following are comments from the RGCT meeting of July 13, 1995.

General Comments

1. Testing Vocabulary should include vocabulary from NIST FIPS documents 151 and NIST NVLAP (National Voluntary Laboratory Accreditation Program) documents.
2. The Source shown in the document shows a FIPS without these being referenced in Section 2.
3. Section 4 was not received with the document reviewed. It was not clear whether or not we received a complete document.

Section 2

1. ISO/IEC DIS 13210:1994 should be ISO/IEC IS 13210:1994
2. ISO/IEC DTR 10000-1.3:1994 - What does 10000-1.3 mean? Should it just be 10000-1:1994. Source for some terms is listed as ISO/IEC DTR 10000-1: 1995. This is different than what is shown here.
3. IEEE P2003:1994 - Does this just mean P2003 Draft 6? The IEEE POSIX Test Methods Standards include IEEE 1003.3:1991 (ISO/IEC IS 13210), IEEE P2003 Draft 6, IEEE 2003.1:1992 (ISO/IEC CD 14515-1), IEEE P2003.1b Draft 4, IEEE P2003.2 Draft 10 (ISO/IEC R&C 14515-2), and IEEE P2003.5 Draft 1. Under Section 3 several items seem to reference this as the source but came from documents other than P2003 Draft 6. In some cases the vocabulary seems to come from a Base POSIX standard and not from the Test Methods Standard. The IEEE Test Methods group tries not to redefine something that has been defined in a base standard. IEEE P2003 Draft 6 has in many cases changed the meaning of terms used in IEEE 1003.3 (ISO/IEC 13210) in order to make them applicable to Profile Testing as well as to meet the International objections that the current definitions were too specific to the POSIX standards.

Section 3

1. alternative behaviour - Not a defined term in ISO/IEC IS 13210, or IEEE P2003 Draft 6, or IEEE 2003.1: 1992.
2. application portability interface, API - Source reference is wrong, probably should be ISO/IEC 9945-1
3. assertion - Source reference should be ISO/IEC IS 13210. The word "form" should be "from". This definition has been changed in P2003 Draft 6.
4. assertion number - Source reference should be ISO/IEC IS 13210. This term has been dropped in P2003 Draft 6 and replaced with the term "assertion identifier".
5. assertion test - Source reference should be ISO/IEC IS 13210. The definition has changed in P2003 Draft 6.
6. base standard - Source reference should be ISO/IEC IS 13210. This definition has changed in P2003 Draft 6.
7. conformance document - Source reference should be ISO/IEC IS 13210. This definition has changed in P2003 Draft 6.
8. conforming application - This definition should be reference to ISO/IEC 9945-1 and picked up from there. IEEE POSIX Test Methods did not redefine terms used in base standards.
9. development system - Source reference should be ISO/IEC IS 13210. This term has changed in P2003 Draft 6 to "Build System".
10. documentation assertion - Source reference should be ISO/IEC IS 13210. This term has changed in P2003 Draft 6.
11. element - Source reference should be ISO/IEC IS 13210. This term has changed in P2003 Draft 6.
12. implementation under test - Source reference should be ISO/IEC IS 13210. This definition has changed in P2003 Draft 6.
13. NVLAP - National Voluntary Laboratory Accreditation Program needs to be added.
14. option - Source reference should be ISO/IEC IS 13210. This definition has changed in P2003 Draft 6.
15. POSIX conformance document, PCD - Source reference should be ISO/IEC IS 13210. This definition has changed in P2003 Draft 6 to just "conformance document".
16. POSIX conformance test procedure, PCTP - Source reference should be ISO/IEC IS 13210. This definition has changed in P2003 Draft 6 to just "conformance test procedure".
17. POSIX conformance test suite, PCTS - Source reference should be ISO/IEC IS 13210. This definition has changed in P2003 Draft 6 to "conformance test suite".
18. system under test, SUT - Source reference should be ISO/IEC IS 13210.
19. target system - Source reference should be ISO/IEC IS 13210. This definition has removed in P2003 Draft 6.

20. target system support facilities - Not a defined term in ISO/IEC IS 13210, or IEEE P2003 Draft 6, or IEEE 2003.1: 1992.
21. test method - Source reference should be ISO/IEC IS 13210. This definition has been removed in P2003 Draft 6.
22. test result code - Source reference should be ISO/IEC IS 13210.
23. testing constant - Source reference should be IEEE P2003 Draft 6.
24. undefined - This is not a Test Methods definition but is defined in ISO/IEC 9945-1.
25. unspecified - This is not a Test Methods definition, but is defined in ISO/IEC 9945-1.